

Notice of References Cited

Application/Control No.

10/574,389

Applicant(s)/Patent Under

Reexamination

MIRLACH ET AL.

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FORREST M. PHILLIPS

Art Unit

2837

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-3,388,770 A	06-1968	STRAW ELDRED G	181/228
*	B US-6,135,237 A	10-2000	Allman, James R.	181/282
*	C US-2001/0018995 A1	09-2001	Uegane, Masayuki	181/275
*	D US-2001/0045322 A1	11-2001	Nilsson et al.	181/227
*	E US-6,382,347 B1	05-2002	Gerber, Brian H.	181/227
*	F US-6,571,911 B2	06-2003	Watanabe et al.	181/265
*	G US-6,598,390 B2	07-2003	Chang, Ming-Tien	60/323
*	H US-6,651,773 B1	11-2003	Marocco, Gregory M.	181/270
*	I US-6,644,437 B1	11-2003	Hayman, Alan William	181/268
*	J US-6,755,279 B2	06-2004	Kaneko et al.	181/232
*	K US-6,935,461 B2	08-2005	Marocco, Gregory M.	181/270
*	L US-6,942,061 B2	09-2005	Butterfield et al.	181/275
*	M US-7,004,283 B2	02-2006	Werner et al.	181/239

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 03067012 A	03-1991	Japan	HIRATSUKA, KOUTAROU	F01N 01/02
O	JP 05106432 A	04-1993	Japan	KATSUMATA et al.	F01N 07/08
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2006/0162995 A1	07-2006	Schorn et al.	181/237
*	B US-7,287,622 B2	10-2007	Rauch et al.	181/272
*	C US-7,377,359 B2	05-2008	Hofmann et al.	181/275
*	D US-7,380,635 B2	06-2008	Harris, Gregory Leigh	181/206
*	E US-7,380,637 B2	06-2008	Sieben et al.	181/240
*	F US-7,416,052 B2	08-2008	Mabuchi et al.	181/272
*	G US-7,503,427 B2	03-2009	Toyoshima, Youhei	181/272
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
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